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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/654,784	09/04/2003	Andrea S. Rivers	86174RLO	5501

7590 09/07/2005  
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EXAMINER

COLEMAN, WILLIAM D

ART UNIT PAPER NUMBER

2823

DATE MAILED: 09/07/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

# Office Action Summary

Application No.

10/654,784

Applicant(s)

RIVERS ET AL.

Examiner

W. David Coleman

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-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --  
Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

## Status

- 1) ☒ Responsive to communication(s) filed on 26 August 2005.
- 2a) ☐ This action is FINAL. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

## Disposition of Claims

- 4) ☒ Claim(s) 1-8 is/are pending in the application.
- 4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.
- 5) ☐ Claim(s) \_\_\_\_\_ is/are allowed.
- 6) ☒ Claim(s) 1-8 is/are rejected.
- 7) ☐ Claim(s) \_\_\_\_\_ is/are objected to.
- 8) ☐ Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

## Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on \_\_\_\_\_ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.  
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

## Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some \* c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- \* See the attached detailed Office action for a list of the certified copies not received.

## Attachment(s)

- 1) ☒ Notice of References Cited (PTO-892)
- 2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) ☒ Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  
Paper No(s)/Mail Date 08/05/09/03
- 4) ☐ Interview Summary (PTO-413)  
Paper No(s)/Mail Date. \_\_\_\_\_
- 5) ☐ Notice of Informal Patent Application (PTO-152)
- 6) ☐ Other: \_\_\_\_\_

**DETAILED ACTION*****Claim Rejections - 35 USC § 102***

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

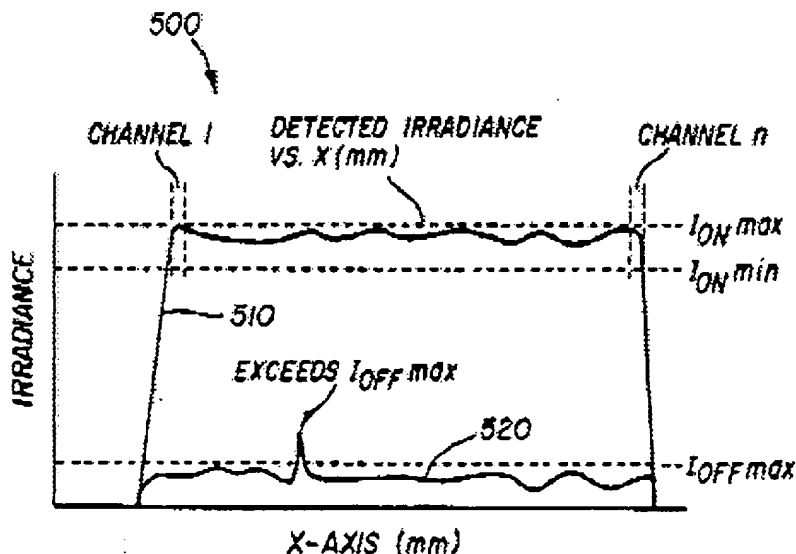
A person shall be entitled to a patent unless –

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

2. Claims 1-8 are rejected under 35 U.S.C. 102(e) as being anticipated by Kay et al., U.S.

Patent 6,844,891.

3. Kay discloses a semiconductor process as claimed. See **FIGS. 1A-8** where Kay teaches the following limitations.



4. Pertaining to claim 1, Kay teaches a method of inspecting an OLED device to locate and characterize defects in the registration of organic materials) transferred from a donor in swaths in

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response to heat produced by a multichannel laser print head, comprising: a) optically inspecting the OLED device after or during manufacture to identify the boundaries between swaths of transferred organic material(s); and b) determining if the swaths overlap at a seam of the boundary or if there is a gap between swath edges at the seam or if there is an offset between the edges of adjacent swaths (need to put in).

5. Pertaining to claim 2, Kay teaches a method of inspecting an OLED device to determine if organic material(s) transferred from a donor in swaths in response to heat produced by a multichannel laser print head have been produced to minimize visual artifacts produced by the OLED device, comprising: a) optically inspecting the OLED device after or during a manufacturing process to identify the boundaries between swaths of transferred organic material(s); b) determining if the swaths overlap at a seam of the boundary or determining if there is a gap between swath edges at the seam or if there is an offset between the edges of adjacent swaths; and c) determining if the overlap, gap or offset are sufficient to require correction in the manufacturing process.

6. Pertaining to claim 3, Kay teaches the method of claim 2 further including correcting the manufacturing process either after the production of the OLED device or during OLED device production in response to the determination if the overlap, gap or offset were sufficient to require manufacturing process correction.

7. Pertaining to claim 4, Kay teaches a method of manufacturing an OLED device comprising: a) operating a multichannel laser print head in response to an image tile to cause the transfer of organic material(s) thermally transferred from a donor in swaths to the OLED device, comprising: b) optically inspecting the OLED device after or during a Manufacturing process to identify the boundaries between swaths of transferred organic material(s); c) determining if the swaths overlap at a seam of the boundary or determining if there is a gap between swath edges at the seam or if there is an offset between the edges of adjacent swaths; and d) correcting the image file if the overlap, gap or offset are sufficient to require correction in the manufacturing process.

8. Pertaining to claim 5, Kay teaches the method of claim 4 further including producing the image tile by using a CAD file and equipment characterization data.

9. Pertaining to claim 6, Kay teaches the method of claim 5 wherein the act of correcting the image artifact includes changing the machine instruction file.

10. Pertaining to claim 7, Kay teaches the method of claim 4 further including determining the distribution of visual artifacts across the OLED device.

11. Pertaining to claim 8, Kay teaches the method of claim 7 further including using the distribution of visual artifacts to identify problems in manufacturing equipment.

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*Conclusion*

12. Any inquiry concerning this communication or earlier communications from the examiner should be directed to W. David Coleman whose telephone number is 571-272-1856.

The examiner can normally be reached on Monday-Friday 9:00 AM - 5:30 PM.

13. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Olik Chaudhuri can be reached on 571-272-1855. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

14. Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).



W. David Coleman  
Primary Examiner  
Art Unit 2823

WDC